



AEGIS
SEMICONDUTORES LTDA.

A1N:25.XXJ

VOLTAGE RATINGS

Part Number	V_{RRM} , V_R (V) Max. rep. peak reverse voltage		V_{RSM} , V_R (V) Max. non-rep. peak reverse voltage
	$T_J = 0$ to 125°C	$T_J = -40$ to 0°C	$T_J = 25$ to 125°C
A1N:25.02J	200	200	300
A1N:25.04J	400	400	500
A1N:25.06J	600	600	700
A1N:25.08J	800	800	900
A1N:25.10J	1000	1000	1100
A1N:25.12J	1200	1200	1300
A1N:25.14J	1400	1330	1500
A1N:25.16J	1600	1520	1700

This datasheet applies to:

Metric thread: A1N:25.XXJ

Inch thread: A2N:25.XXJ

MAXIMUM ALLOWABLE RATINGS

PARAMETER	VALUE	UNITS	NOTES
T_J Junction Temperature	-40 to 125	$^\circ\text{C}$	-
T_{stg} Storage Temperature	-40 to 150	$^\circ\text{C}$	-
$I_{F(AV)}$	25	A	180° half sine wave
	85	$^\circ\text{C}$	
$I_{F(RMS)}$ Nom. RMS current	40	A	-
	0.35	A	50 Hz half cycle sine wave Initial $T_J = 125^\circ\text{C}$, rated V_{RRM} applied after surge.
I_{FSM} Max. Peak non-rep. surge current	0.38		60 Hz half cycle sine wave
	0.4		50 Hz half cycle sine wave Initial $T_J = 125^\circ\text{C}$, no voltage applied after surge.
	0.44		60 Hz half cycle sine wave
	0.51	kA ² s	t = 10ms Initial $T_J = 125^\circ\text{C}$, rated V_{RRM} applied after surge.
I^2t Max. I^2t capability	0.56		t = 8.3 ms
	0.72		t = 10ms Initial $T_J = 125^\circ\text{C}$, no voltage applied after surge.
	0.79		t = 8.3 ms
$I^2t^{1/2}$ Max. $I^2t^{1/2}$ capability	8.67	kA ² s ^{1/2}	Initial $T_J = 125^\circ\text{C}$, no voltage applied after surge. I^2t for time $t_x = I^2t^{1/2} * t_x^{1/2}$. (0.1 < t_x < 10ms).
di/dt Max. Non-repetitive rate-of-rise current	150	A/ s	$T_J = 125^\circ\text{C}$, $V_D = V_{DRM}$, $I_{TM} = 1600\text{A}$. Gate pulse: 20V, 20 , 10 s, 0.5 s rise time, Max. repetitive di/dt is approximately 40% of non-repetitive value.
P_{GM} Max. Peak gate power	8	W	$tp < 5\text{ ms}$
$P_{G(AV)}$ Max. Av. gate power	2	W	-
+ I_{GM} Max. Peak gate current	150	mA	$tp < 5\text{ ms}$
- V_{GM} Max. Peak negative gate voltage	2	V	-
Mounting Force	2.8(25)	N.m(Lbf.in)	Non lubricated threads



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CHARACTERISTICS

PARAMETER	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
V_{TM} peak on-state voltage	---	---	1.79	V	Initial $T_J = 25^\circ\text{C}$, 50-60Hz half sine, $I_{peak} = 79\text{A}$.
$V_{T(TO)}$ Threshold voltage	---	---	0.9	V	$T_J = 125^\circ\text{C}$ Av. power = $V_{T(TO)} * I_{T(AV)} + r_T * [I_{T(RMS)}]^2$, 180° Half Sine.
r_T Slope resistance	---	---	13.5	m	Use low values for $I_{TM} <$ rated $I_{T(AV)}$
I_L Latching current	---	---	200	mA	$T_C = 125^\circ\text{C}$, 12V anode. Gate pulse: 10V, 20 , 100 s.
I_H Holding current	---	---	100	mA	$T_C = 25^\circ\text{C}$, 12V anode. Initial $I_T = 15\text{A}$.
t_d Delay time	---	0.7	1.5	s	$T_C = 25^\circ\text{C}$, $V_D = V_{DRM}$, 50A resistive load. Gate pulse: 10V, 20 , 10 s, 1 s rise time.
t_q Turn-off time	---	125	200	s	$T_J = 125^\circ\text{C}$, $I_{TM} = 500\text{A}$, $dI/dt = 25\text{A}/\text{s}$, $V_R = 50\text{V}$. $dv/dt = 20\text{V}/\text{s}$ lin. to rated V_{DRM} . Gate: 0V, 100 .
dv/dt Critical rate-of-rise of off-state voltage	80	140	---	V/ s	$T_J = 125^\circ\text{C}$. Exp. to 100% or lin. Higher dv/dt values available.
	---	---	200		$T_J = 125^\circ\text{C}$, Exp. To 67% V_{DRM} , gate open.
I_{RM} , I_{DM} Peak reverse and off-state current	---	5	10	mA	$T_J = 125^\circ\text{C}$, Rated V_{RRM} and V_{DRM} , gate open.
I_{GT} DC gate current to trigger	---	---	300	mA	$T_C = -40^\circ\text{C}$
	50	80	150		$T_C = 25^\circ\text{C}$ +12V anode-to-cathode. For recommended
V_{GT} DC gate voltage to trigger	4	---	---	V	$T_C = -40^\circ\text{C}$ gate drive see "Gate Characteristics" figure.
	2	---	---		$T_C = 25^\circ\text{C}$
V_{GD} DC gate voltage not to trigger	---	---	0.2	V	$T_C = 25^\circ\text{C}$, Max. Value which will not trigger with rated V_{DRM} anode.
R_{thJC} Thermal resistance, junction-to-case	---	---	0.75	°C/W	DC operation, single side cooled.
	---	---	0.84	°C/W	180° sine wave, single side cooled.
	---	---	0.89	°C/W	120° rectangular wave, single side cooled.
R_{thCS} Thermal resistance, case-to-sink	---	---	0.35	°C/W	Mtg. Surface smooth, flat and greased. Single side cooled.
wt Weight	---	12(0.48)	---	g(oz.)	---
Case Style	TO-208AA (TO-48)		JEDEC		---

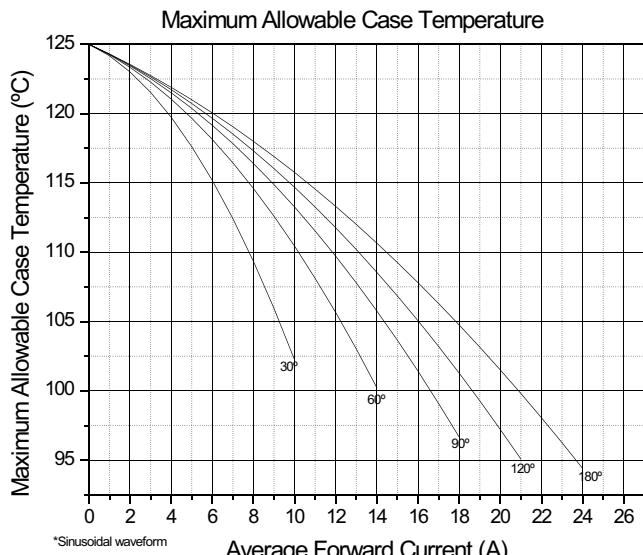


Fig. 1 - Current Ratings Characteristics

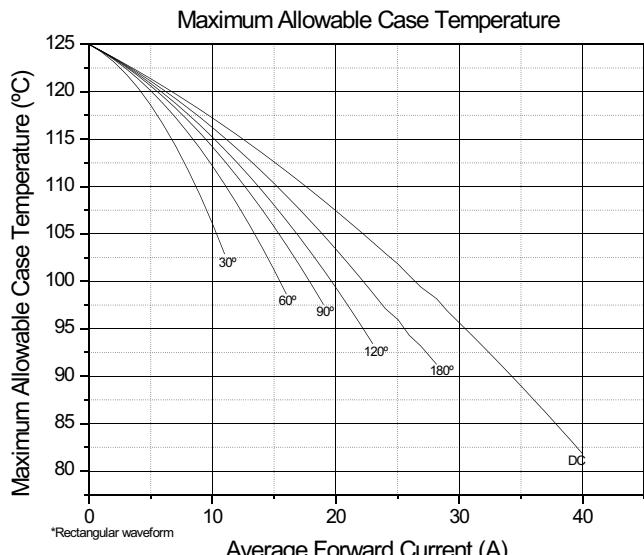


Fig. 2 - Current Ratings Characteristics



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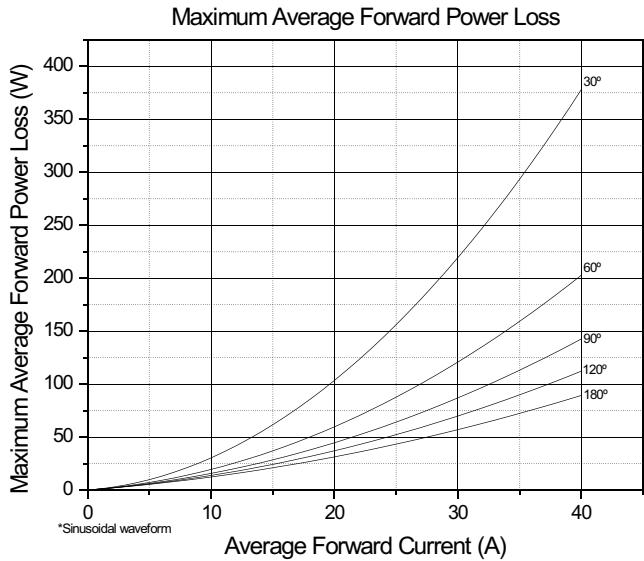


Fig. 3 - Forward Power Loss Characteristics

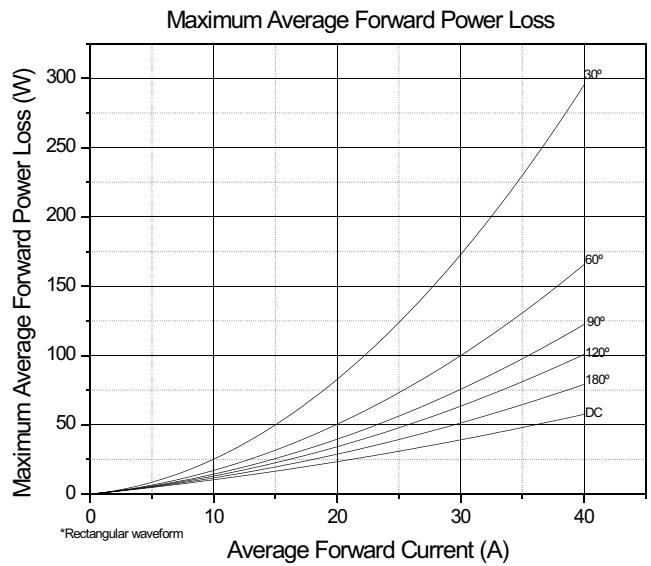


Fig. 4 - Forward Power Loss Characteristics

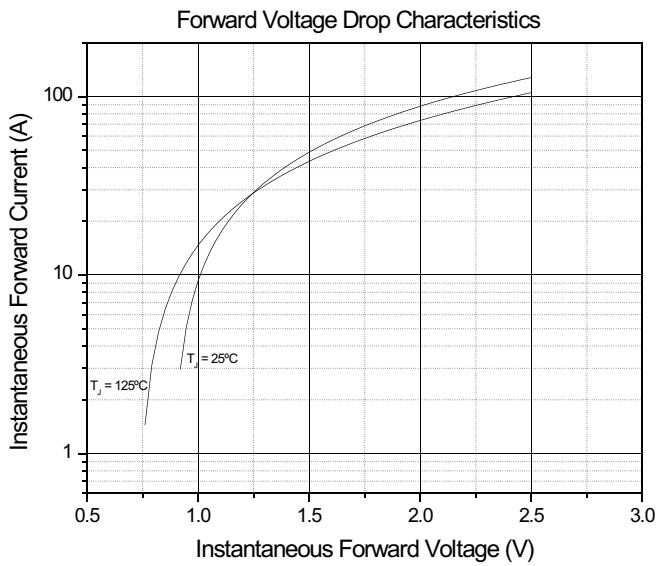


Fig. 5 - Forward Voltage Drop Characteristics

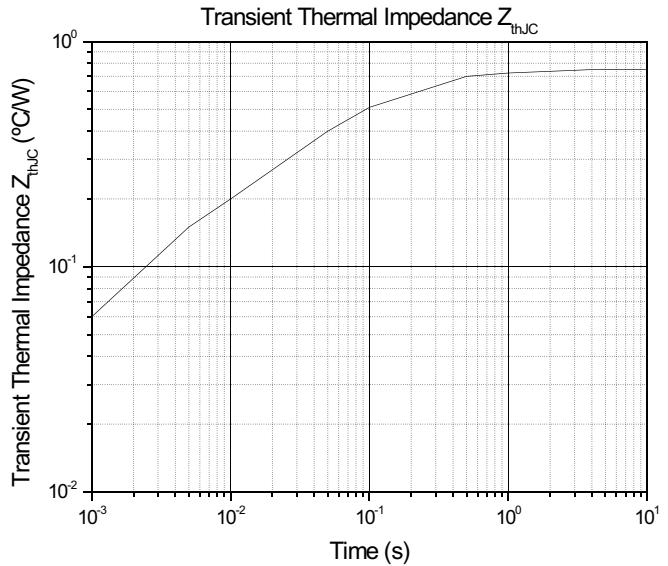


Fig. 6 - Transient Thermal Impedance Characteristics



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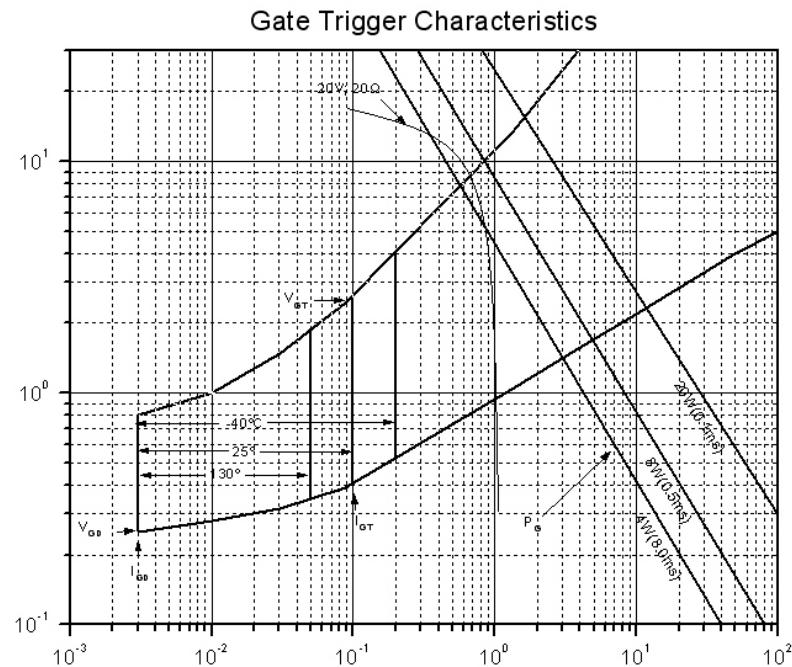


Fig. 7 - Gate Trigger Characteristics

TO-208AA (TO-48)

